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Understanding **Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	31775
Number of Logic Elements/Cells	406720
Total RAM Bits	29306880
Number of I/O	500
Number of Gates	-
Voltage - Supply	0.97V ~ 1.03V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	900-BBGA, FCBGA
Supplier Device Package	900-FCBGA (31x31)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7k410t-2ffv900c

Table 5: Maximum Allowed AC Voltage Overshoot and Undershoot for 1.8V HP I/O Banks⁽¹⁾⁽²⁾ (Cont'd)

AC Voltage Overshoot	% of UI @-40°C to 100°C	AC Voltage Undershoot	% of UI @-40°C to 100°C
V _{CCO} + 0.80	9.71	-0.80	50.0
V _{CCO} + 0.85	4.51	-0.85	28.4
V _{CCO} + 0.90	2.12	-0.90	12.7
V _{CCO} + 0.95	1.01	-0.95	5.79

Notes:

1. A total of 200 mA per bank should not be exceeded.
2. For UI smaller than 20 µs.

Table 6: Typical Quiescent Supply Current

Symbol	Description	Device	Speed Grade				Units	
			1.0V		0.9V			
			-3	-2/-2L	-1	-2L		
I _{CCINTQ}	Quiescent V _{CCINT} supply current	XC7K70T	241	241	241	187	mA	
		XC7K160T	474	474	474	368	mA	
		XC7K325T	810	810	810	629	mA	
		XC7K355T	993	993	993	771	mA	
		XC7K410T	1080	1080	1080	838	mA	
		XC7K420T	1313	1313	1313	1019	mA	
		XC7K480T	1313	1313	1313	1019	mA	
I _{CCOQ}	Quiescent V _{CCO} supply current	XC7K70T	1	1	1	1	mA	
		XC7K160T	1	1	1	1	mA	
		XC7K325T	1	1	1	1	mA	
		XC7K355T	1	1	1	1	mA	
		XC7K410T	1	1	1	1	mA	
		XC7K420T	1	1	1	1	mA	
		XC7K480T	1	1	1	1	mA	
I _{CCAUXQ}	Quiescent V _{CCAUX} supply current	XC7K70T	21	21	21	21	mA	
		XC7K160T	40	40	40	40	mA	
		XC7K325T	68	68	68	68	mA	
		XC7K355T	75	75	75	75	mA	
		XC7K410T	85	85	85	85	mA	
		XC7K420T	99	99	99	99	mA	
		XC7K480T	99	99	99	99	mA	
I _{CCAUX_IOQ}	Quiescent V _{CCAUX_IO} supply current	XC7K70T	N/A	N/A	N/A	N/A	mA	
		XC7K160T	2	2	2	2	mA	
		XC7K325T	2	2	2	2	mA	
		XC7K355T	N/A	N/A	N/A	N/A	mA	
		XC7K410T	2	2	2	2	mA	
		XC7K420T	N/A	N/A	N/A	N/A	mA	
		XC7K480T	N/A	N/A	N/A	N/A	mA	

Table 10: Differential SelectIO DC Input and Output Levels

I/O Standard	V _{ICM} ⁽¹⁾			V _{ID} ⁽²⁾			V _{OCM} ⁽³⁾			V _{OD} ⁽⁴⁾		
	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max	V, Min	V, Typ	V, Max
BLVDS_25	0.300	1.200	1.425	0.100	—	—	—	1.250	—	Note 5		
MINI_LVDS_25	0.300	1.200	V _{CCAUX}	0.200	0.400	0.600	1.000	1.200	1.400	0.300	0.450	0.600
PPDS_25	0.200	0.900	V _{CCAUX}	0.100	0.250	0.400	0.500	0.950	1.400	0.100	0.250	0.400
RSDS_25	0.300	0.900	1.500	0.100	0.350	0.600	1.000	1.200	1.400	0.100	0.350	0.600
TMDS_33	2.700	2.965	3.230	0.150	0.675	1.200	V _{CCO} –0.405	V _{CCO} –0.300	V _{CCO} –0.190	0.400	0.600	0.800

Notes:

1. V_{ICM} is the input common mode voltage.
2. V_{ID} is the input differential voltage (Q – \bar{Q}).
3. V_{OCM} is the output common mode voltage.
4. V_{OD} is the output differential voltage (Q – \bar{Q}).
5. V_{OD} for BLVDS will vary significantly depending on topology and loading.
6. LVDS_25 is specified in Table 12.
7. LVDS is specified in Table 13.

Table 11: Complementary Differential SelectIO DC Input and Output Levels

I/O Standard	V _{ICM} ⁽¹⁾			V _{ID} ⁽²⁾			V _{OL} ⁽³⁾		V _{OH} ⁽⁴⁾		I _{OL}		I _{OH}
	V, Min	V, Typ	V, Max	V, Min	V, Max	V, Max	V, Min	mA, Max	mA, Min	V, Min	mA, Max	mA, Min	
DIFF_HSTL_I	0.300	0.750	1.125	0.100	—	0.400	V _{CCO} –0.400	8.00	—8.00				
DIFF_HSTL_I_18	0.300	0.900	1.425	0.100	—	0.400	V _{CCO} –0.400	8.00	—8.00				
DIFF_HSTL_II	0.300	0.750	1.125	0.100	—	0.400	V _{CCO} –0.400	16.00	—16.00				
DIFF_HSTL_II_18	0.300	0.900	1.425	0.100	—	0.400	V _{CCO} –0.400	16.00	—16.00				
DIFF_HSUL_12	0.300	0.600	0.850	0.100	—	20% V _{CCO}	80% V _{CCO}	0.100	—0.100				
DIFF_MOBILE_DDR	0.300	0.900	1.425	0.100	—	10% V _{CCO}	90% V _{CCO}	0.100	—0.100				
DIFF_SSTL12	0.300	0.600	0.850	0.100	—	(V _{CCO} /2) – 0.150	(V _{CCO} /2) + 0.150	14.25	—14.25				
DIFF_SSTL135	0.300	0.675	1.000	0.100	—	(V _{CCO} /2) – 0.150	(V _{CCO} /2) + 0.150	13.0	—13.0				
DIFF_SSTL135_R	0.300	0.675	1.000	0.100	—	(V _{CCO} /2) – 0.150	(V _{CCO} /2) + 0.150	8.9	—8.9				
DIFF_SSTL15	0.300	0.750	1.125	0.100	—	(V _{CCO} /2) – 0.175	(V _{CCO} /2) + 0.175	13.0	—13.0				
DIFF_SSTL15_R	0.300	0.750	1.125	0.100	—	(V _{CCO} /2) – 0.175	(V _{CCO} /2) + 0.175	8.9	—8.9				
DIFF_SSTL18_I	0.300	0.900	1.425	0.100	—	(V _{CCO} /2) – 0.470	(V _{CCO} /2) + 0.470	8.00	—8.00				
DIFF_SSTL18_II	0.300	0.900	1.425	0.100	—	(V _{CCO} /2) – 0.600	(V _{CCO} /2) + 0.600	13.4	—13.4				

Notes:

1. V_{ICM} is the input common mode voltage.
2. V_{ID} is the input differential voltage (Q – \bar{Q}).
3. V_{OL} is the single-ended low-output voltage.
4. V_{OH} is the single-ended high-output voltage.

LVDS DC Specifications (LVDS_25)

The LVDS_25 standard is available in the HR I/O banks. See [UG471: 7 Series FPGAs SelectIO Resources User Guide](#) for more information.

Table 12: LVDS_25 DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.375	2.500	2.625	V
V_{OH}	Output High Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	–	–	1.675	V
V_{OL}	Output Low Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	0.700	–	–	V
V_{ODIFF}	Differential Output Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High	$R_T = 100 \Omega$ across Q and \bar{Q} signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage	$R_T = 100 \Omega$ across Q and \bar{Q} signals	1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High		100	350	600	mV
V_{ICM}	Input Common-Mode Voltage		0.300	1.200	1.425	V

LVDS DC Specifications (LVDS)

The LVDS standard is available in the HP I/O banks. See [UG471: 7 Series FPGAs SelectIO Resources User Guide](#) for more information.

Table 13: LVDS DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		1.710	1.800	1.890	V
V_{OH}	Output High Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	–	–	1.675	V
V_{OL}	Output Low Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	0.825	–	–	V
V_{ODIFF}	Differential Output Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High	$R_T = 100 \Omega$ across Q and \bar{Q} signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage	$R_T = 100 \Omega$ across Q and \bar{Q} signals	1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High	Common-mode input voltage = 1.25V	100	350	600	mV
V_{ICM}	Input Common-Mode Voltage	Differential input voltage = ± 350 mV	0.300	1.200	1.425	V

AC Switching Characteristics

All values represented in this data sheet are based on the speed specifications in ISE® software 14.3 v1.07 for the -3, -2, -2L(1.0V), -1, and v1.06 for -2L(0.9V) speed grades.

Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance Product Specification

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary Product Specification

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Product Specification

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to production before faster speed grades.

Testing of AC Switching Characteristics

Internal timing parameters are derived from measuring internal test patterns. All AC switching characteristics are representative of worst-case supply voltage and junction temperature conditions.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Kintex-7 FPGAs.

Speed Grade Designations

Since individual family members are produced at different times, the migration from one category to another depends completely on the status of the fabrication process for each device. [Table 14](#) correlates the current status of each Kintex-7 device on a per speed grade basis.

Table 14: Kintex-7 Device Speed Grade Designations

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XC7K70T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K160T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K325T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K355T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K410T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K420T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K480T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)

Table 17: Maximum Physical Interface (PHY) Rate for Memory Interfaces (FFG Packages)⁽¹⁾⁽²⁾

Memory Standard	I/O Bank Type	V _{CCAUX_IO}	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
4:1 Memory Controllers							
DDR3	HP	2.0V	1866	1866	1600	1333	Mb/s
	HP	1.8V	1600	1333	1066	1066	Mb/s
	HR	N/A	1066	1066	800	800	Mb/s
DDR3L	HP	2.0V	1600	1600	1333	1066	Mb/s
	HP	1.8V	1333	1066	800	800	Mb/s
	HR	N/A	800	800	667	667	Mb/s
DDR2	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V	800	800	800	800	Mb/s
	HR	N/A	800	800	800	800	Mb/s
RLDRAM III ⁽³⁾	HP	2.0V	800	667	667	533	MHz
	HP	1.8V	550	500	450	450	MHz
	HR	N/A			N/A		
2:1 Memory Controllers							
DDR3	HP	2.0V	1066	1066	800	800	Mb/s
	HP	1.8V	1066	1066	800	800	Mb/s
	HR	N/A	1066	1066	800	800	Mb/s
DDR3L	HP	2.0V	1066	1066	800	800	Mb/s
	HP	1.8V	1066	1066	800	800	Mb/s
	HR	N/A	800	800	667	667	Mb/s
DDR2	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V					
	HR	N/A					
QDR II+ ⁽⁴⁾	HP	2.0V	550	500	450	450	MHz
	HP	1.8V					
	HR	N/A					
RLDRAM II	HP	2.0V	533	500	450	450	MHz
	HP	1.8V					
	HR	N/A					
LPDDR2 ⁽³⁾	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V	800	800	800	800	Mb/s
	HR	N/A	800	667	667	667	Mb/s

Notes:

1. V_{REF} tracking is required. For more information, see [UG586, 7 Series FPGAs Memory Interface Solutions User Guide](#).
2. When using the internal V_{REF} the maximum data rate is 800 Mb/s (400 MHz).
3. RLDRAM III (BL = 4, BL = 8) and LPDDR2 specifications have not been validated with memory IP.
4. The maximum QDRII+ performance specifications are for burst-length 4 (BL = 4) implementations. Burst length 2 (BL = 2) implementations are limited to 333 MHz for all speed grades and I/O bank types.

IOB Pad Input/Output/3-State

Table 19 (3.3V high-range IOB (HR)) and **Table 20** (1.8V high-performance IOB (HP)) summarizes the values of standard-specific data input delay adjustments, output delays terminating at pads (based on standard) and 3-state delays.

- T_{IOP} is described as the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.
- T_{IOOP} is described as the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.
- T_{IOTP} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer. In HP I/O banks, the internal DCI termination turn-on time is always faster than T_{IOTP} when the DCITERMDISABLE pin is used. In HR I/O banks, the IN_TERM termination turn-on time is always faster than T_{IOTP} when the INTERMDISABLE pin is used.

Table 19: 3.3V IOB High Range (HR) Switching Characteristics

I/O Standard	T_{IOP}				T_{IOOP}				T_{IOTP}				Units	
	Speed Grade			Speed Grade			Speed Grade			Speed Grade				
	1.0V		0.9V	1.0V		0.9V	1.0V		0.9V	Speed Grade				
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L		
LVTTL_S4	1.31	1.42	1.64	1.51	5.27	5.63	6.05	4.13	6.03	6.49	7.04	4.64	ns	
LVTTL_S8	1.31	1.42	1.64	1.51	4.45	4.83	5.30	3.86	5.21	5.69	6.29	4.38	ns	
LVTTL_S12	1.31	1.42	1.64	1.51	4.45	4.83	5.29	3.84	5.21	5.69	6.28	4.36	ns	
LVTTL_S16	1.31	1.42	1.64	1.51	3.47	3.88	4.40	3.39	4.23	4.74	5.39	3.91	ns	
LVTTL_S24	1.31	1.42	1.64	1.51	3.58	3.99	4.51	3.61	4.34	4.85	5.50	4.13	ns	
LVTTL_F4	1.31	1.42	1.64	1.51	4.70	4.98	5.29	3.58	5.46	5.84	6.28	4.09	ns	
LVTTL_F8	1.31	1.42	1.64	1.51	3.66	4.06	4.56	3.06	4.42	4.92	5.55	3.58	ns	
LVTTL_F12	1.31	1.42	1.64	1.51	3.66	4.06	4.56	3.05	4.42	4.92	5.55	3.56	ns	
LVTTL_F16	1.31	1.42	1.64	1.51	2.57	2.85	3.15	2.88	3.33	3.71	4.14	3.39	ns	
LVTTL_F24	1.31	1.42	1.64	1.51	2.41	2.64	2.89	2.94	3.17	3.50	3.88	3.45	ns	
LVDS_25 ⁽¹⁾	0.64	0.68	0.80	0.83	1.36	1.47	1.55	1.58	2.12	2.33	2.54	2.09	ns	
MINI_LVDS_25	0.68	0.70	0.79	0.83	1.36	1.47	1.55	1.59	2.12	2.33	2.54	2.11	ns	
BLVDS_25 ⁽¹⁾	0.65	0.69	0.80	0.83	1.83	2.02	2.20	2.16	2.59	2.88	3.19	2.67	ns	
RSDS_25 (point to point) ⁽¹⁾	0.63	0.68	0.79	0.83	1.36	1.48	1.55	1.59	2.12	2.34	2.54	2.11	ns	
PPDS_25 ⁽¹⁾	0.65	0.69	0.80	0.83	1.36	1.49	1.58	1.59	2.12	2.35	2.57	2.11	ns	
TMDS_33 ⁽¹⁾	0.72	0.76	0.86	0.83	1.43	1.54	1.60	1.70	2.19	2.40	2.59	2.22	ns	
PCI33_3 ⁽¹⁾	1.28	1.41	1.65	1.50	2.71	3.08	3.52	3.42	3.47	3.94	4.51	3.94	ns	
HSUL_12	0.63	0.64	0.71	0.79	2.06	2.31	2.59	2.13	2.82	3.17	3.58	2.64	ns	
DIFF_HSUL_12	0.58	0.61	0.70	0.81	1.83	2.04	2.26	1.92	2.59	2.90	3.25	2.44	ns	
HSTL_I_S	0.61	0.64	0.73	0.79	1.55	1.69	1.80	1.91	2.31	2.55	2.79	2.42	ns	
HSTL_II_S	0.61	0.64	0.73	0.78	1.21	1.34	1.43	1.70	1.97	2.20	2.42	2.22	ns	
HSTL_I_18_S	0.64	0.67	0.76	0.79	1.28	1.39	1.45	1.58	2.04	2.25	2.44	2.09	ns	
HSTL_II_18_S	0.64	0.67	0.76	0.79	1.18	1.31	1.40	1.69	1.94	2.17	2.39	2.20	ns	
DIFF_HSTL_I_S	0.63	0.67	0.77	0.78	1.42	1.54	1.61	1.84	2.18	2.40	2.60	2.36	ns	
DIFF_HSTL_II_S	0.63	0.67	0.77	0.79	1.15	1.24	1.27	1.78	1.91	2.10	2.26	2.30	ns	
DIFF_HSTL_I_18_S	0.65	0.69	0.78	0.79	1.27	1.38	1.43	1.67	2.03	2.24	2.42	2.19	ns	
DIFF_HSTL_II_18_S	0.65	0.69	0.78	0.81	1.14	1.23	1.26	1.72	1.90	2.09	2.25	2.23	ns	

Table 20: 1.8V IOB High Performance (HP) Switching Characteristics (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units	
	Speed Grade				Speed Grade				Speed Grade					
	1.0V		0.9V		1.0V		0.9V		1.0V		0.9V			
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L		
DIFF_HSTL_II_DCI_F	0.75	0.79	0.92	0.76	0.97	1.08	1.15	1.30	1.61	1.84	1.97	1.91	ns	
DIFF_HSTL_I_18_F	0.75	0.79	0.92	0.89	1.04	1.16	1.24	1.38	1.68	1.91	2.06	1.99	ns	
DIFF_HSTL_II_18_F	0.75	0.79	0.92	0.89	0.98	1.09	1.16	1.40	1.62	1.85	1.98	2.01	ns	
DIFF_HSTL_I_DCI_18_F	0.75	0.79	0.92	0.75	1.04	1.16	1.24	1.38	1.67	1.91	2.06	1.99	ns	
DIFF_HSTL_II_DCI_18_F	0.75	0.79	0.92	0.75	0.98	1.09	1.16	1.33	1.61	1.85	1.98	1.94	ns	
DIFF_HSTL_II_T_DCI_18_F	0.75	0.79	0.92	0.76	1.04	1.16	1.24	1.38	1.67	1.91	2.06	1.99	ns	
LVCMOS18_S2	0.47	0.50	0.60	0.87	3.95	4.28	4.85	3.40	4.59	5.04	5.67	4.01	ns	
LVCMOS18_S4	0.47	0.50	0.60	0.87	2.67	2.98	3.43	2.69	3.31	3.73	4.26	3.30	ns	
LVCMOS18_S6	0.47	0.50	0.60	0.87	2.14	2.38	2.72	2.18	2.77	3.14	3.54	2.79	ns	
LVCMOS18_S8	0.47	0.50	0.60	0.87	1.98	2.21	2.52	2.02	2.61	2.97	3.35	2.63	ns	
LVCMOS18_S12	0.47	0.50	0.60	0.87	1.70	1.91	2.17	1.85	2.34	2.67	2.99	2.46	ns	
LVCMOS18_S16	0.47	0.50	0.60	0.87	1.57	1.75	1.97	1.76	2.20	2.51	2.79	2.37	ns	
LVCMOS18_F2	0.47	0.50	0.60	0.87	3.50	3.87	4.48	2.85	4.14	4.63	5.30	3.46	ns	
LVCMOS18_F4	0.47	0.50	0.60	0.87	2.23	2.50	2.87	2.26	2.87	3.25	3.69	2.87	ns	
LVCMOS18_F6	0.47	0.50	0.60	0.87	1.80	2.00	2.26	1.52	2.43	2.76	3.08	2.13	ns	
LVCMOS18_F8	0.47	0.50	0.60	0.87	1.46	1.72	2.04	1.51	2.10	2.47	2.86	2.12	ns	
LVCMOS18_F12	0.47	0.50	0.60	0.87	1.26	1.40	1.53	1.46	1.89	2.16	2.35	2.07	ns	
LVCMOS18_F16	0.47	0.50	0.60	0.87	1.19	1.33	1.44	1.46	1.83	2.08	2.26	2.07	ns	
LVCMOS15_S2	0.59	0.62	0.73	0.86	3.55	3.89	4.45	3.11	4.19	4.65	5.27	3.73	ns	
LVCMOS15_S4	0.59	0.62	0.73	0.86	2.45	2.70	3.06	2.46	3.08	3.45	3.89	3.07	ns	
LVCMOS15_S6	0.59	0.62	0.73	0.86	2.24	2.51	2.88	2.33	2.88	3.26	3.71	2.94	ns	
LVCMOS15_S8	0.59	0.62	0.73	0.86	1.91	2.16	2.49	2.05	2.55	2.91	3.31	2.66	ns	
LVCMOS15_S12	0.59	0.62	0.73	0.86	1.77	1.98	2.23	1.97	2.41	2.73	3.05	2.58	ns	
LVCMOS15_S16	0.59	0.62	0.73	0.86	1.62	1.81	2.02	1.85	2.26	2.56	2.84	2.46	ns	
LVCMOS15_F2	0.59	0.62	0.73	0.86	3.38	3.69	4.18	2.74	4.02	4.44	5.00	3.35	ns	
LVCMOS15_F4	0.59	0.62	0.73	0.86	2.04	2.21	2.44	1.72	2.68	2.97	3.26	2.33	ns	
LVCMOS15_F6	0.59	0.62	0.73	0.86	1.47	1.74	2.09	1.49	2.10	2.50	2.91	2.10	ns	
LVCMOS15_F8	0.59	0.62	0.73	0.86	1.31	1.46	1.61	1.47	1.95	2.22	2.43	2.08	ns	
LVCMOS15_F12	0.59	0.62	0.73	0.86	1.21	1.34	1.45	1.44	1.84	2.10	2.27	2.05	ns	
LVCMOS15_F16	0.59	0.62	0.73	0.86	1.18	1.31	1.41	1.41	1.82	2.07	2.23	2.02	ns	
LVCMOS12_S2	0.64	0.67	0.78	0.95	3.38	3.80	4.48	3.27	4.02	4.55	5.30	3.88	ns	
LVCMOS12_S4	0.64	0.67	0.78	0.95	2.62	2.94	3.43	2.76	3.26	3.70	4.25	3.37	ns	
LVCMOS12_S6	0.64	0.67	0.78	0.95	2.05	2.33	2.72	2.24	2.69	3.08	3.54	2.85	ns	
LVCMOS12_S8	0.64	0.67	0.78	0.95	1.94	2.18	2.51	2.16	2.58	2.94	3.33	2.77	ns	
LVCMOS12_F2	0.64	0.67	0.78	0.95	2.84	3.15	3.62	2.47	3.48	3.90	4.44	3.08	ns	
LVCMOS12_F4	0.64	0.67	0.78	0.95	1.97	2.18	2.44	1.69	2.61	2.93	3.26	2.30	ns	
LVCMOS12_F6	0.64	0.67	0.78	0.95	1.33	1.51	1.70	1.43	1.96	2.26	2.52	2.04	ns	

Table 23: OLOGIC Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Setup/Hold						
TODCK/TOCKD	D1/D2 pins Setup/Hold with respect to CLK	0.45/-0.13	0.50/-0.13	0.58/-0.13	0.79/-0.18	ns
TOOCECK/TOCKOCE	OCE pin Setup/Hold with respect to CLK	0.28/0.03	0.29/0.03	0.45/0.03	0.35/-0.10	ns
TOSRCK/TOCKSR	SR pin Setup/Hold with respect to CLK	0.32/0.18	0.38/0.18	0.70/0.18	0.62/-0.04	ns
TOTCK/TOCKT	T1/T2 pins Setup/Hold with respect to CLK	0.49/-0.16	0.56/-0.16	0.68/-0.16	0.67/-0.18	ns
TOTCECK/TOCKTCE	TCE pin Setup/Hold with respect to CLK	0.28/0.01	0.30/0.01	0.45/0.01	0.31/-0.10	ns
Combinatorial						
TODQ	D1 to OQ out or T1 to TQ out	0.73	0.81	0.97	1.18	ns
Sequential Delays						
TOCKQ	CLK to OQ/TQ out	0.41	0.43	0.49	0.63	ns
TRQ_OLOGICE2	SR pin to OQ/TQ out (HP I/O banks only)	0.63	0.70	0.83	1.12	ns
TGSRQ_OLOGICE2	Global Set/Reset to Q outputs (HP I/O banks only)	7.60	7.60	10.51	11.39	ns
TRQ_OLOGICE3	SR pin to OQ/TQ out (HR I/O banks only)	0.63	0.70	0.83	1.12	ns
TGSRQ_OLOGICE3	Global Set/Reset to Q outputs (HR I/O banks only)	7.60	7.60	10.51	11.39	ns
Set/Reset						
TRPW_OLOGICE2	Minimum Pulse Width, SR inputs (HP I/O banks only)	0.54	0.54	0.63	0.68	ns, Min
TRPW_OLOGICE3	Minimum Pulse Width, SR inputs (HR I/O banks only)	0.54	0.54	0.63	0.68	ns, Min

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 29: CLB Distributed RAM Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Sequential Delays						
T _{SHCKO}	Clock to A – B outputs	0.68	0.70	0.85	1.08	ns, Max
T _{SHCKO_1}	Clock to AMUX – BMUX outputs	0.91	0.95	1.15	1.44	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{DS_LRAM} /T _{DH_LRAM}	A – D inputs to CLK	0.45/0.23	0.45/0.24	0.54/0.27	0.69/0.33	ns, Min
T _{AS_LRAM} /T _{AH_LRAM}	Address An inputs to clock	0.13/0.50	0.14/0.50	0.17/0.58	0.21/0.63	ns, Min
	Address An inputs through MUXs and/or carry logic to clock	0.40/0.16	0.42/0.17	0.52/0.23	0.63/0.23	ns, Min
T _{WS_LRAM} /T _{WH_LRAM}	WE input to clock	0.29/0.09	0.30/0.09	0.36/0.09	0.46/0.10	ns, Min
T _{CECK_LRAM} / T _{CKCE_LRAM}	CE input to CLK	0.29/0.09	0.30/0.09	0.37/0.09	0.47/0.10	ns, Min
Clock CLK						
T _{MPW}	Minimum pulse width	0.68	0.77	0.91	1.11	ns, Min
T _{MCP}	Minimum clock period	1.35	1.54	1.82	2.22	ns, Min

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time.
2. T_{SHCKO} also represents the CLK to XMUX output. Refer to TRACE report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 30: CLB Shift Register Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Sequential Delays						
T _{REG}	Clock to A – D outputs	0.96	0.98	1.20	1.35	ns, Max
T _{REG_MUX}	Clock to AMUX – DMUX output	1.19	1.23	1.50	1.72	ns, Max
T _{REG_M31}	Clock to DMUX output via M31 output	0.89	0.91	1.10	1.25	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{WS_SHFREG} / T _{WH_SHFREG}	WE input	0.26/0.09	0.27/0.09	0.33/0.09	0.41/0.10	ns, Min
T _{CECK_SHFREG} / T _{CKCE_SHFREG}	CE input to CLK	0.27/0.09	0.28/0.09	0.33/0.09	0.42/0.10	ns, Min
T _{DS_SHFREG} / T _{DH_SHFREG}	A – D inputs to CLK	0.28/0.26	0.28/0.26	0.33/0.30	0.41/0.36	ns, Min
Clock CLK						
T _{MPW_SHFREG}	Minimum pulse width	0.55	0.65	0.78	0.91	ns, Min

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time.

Table 31: Block RAM and FIFO Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T _{RCKC_RSTRAM} /T _{RCKC_RSTRAM}	Synchronous RSTRAM input	0.27/0.35	0.29/0.37	0.31/0.39	0.34/0.40	ns, Min
T _{RCKC_WEA} /T _{RCKC_WEA}	Write Enable (WE) input (Block RAM only)	0.38/0.15	0.41/0.16	0.46/0.17	0.54/0.19	ns, Min
T _{RCKC_WREN} /T _{RCKC_WREN}	WREN FIFO inputs	0.39/0.25	0.39/0.30	0.40/0.37	0.65/0.37	ns, Min
T _{RCKC_RDEN} /T _{RCKC_RDEN}	RDEN FIFO inputs	0.36/0.26	0.36/0.30	0.37/0.37	0.60/0.38	ns, Min
Reset Delays						
T _{RCO_FLAGS}	Reset RST to FIFO flags/pointers ⁽¹⁰⁾	0.76	0.83	0.93	1.06	ns, Max
T _{RREC_RST} /T _{RREM_RST}	FIFO reset recovery and removal timing ⁽¹¹⁾	1.59/-0.68	1.76/-0.68	2.01/-0.68	2.07/-0.60	ns, Max
Maximum Frequency						
F _{MAX_BRAM_WF_NC}	Block RAM (Write first and No change modes) When not in SDP RF mode	601.32	543.77	458.09	372.44	MHz
F _{MAX_BRAM_RF_PERFORMANCE}	Block RAM (Read first, Performance mode) When in SDP RF mode but no address overlap between port A and port B	601.32	543.77	458.09	372.44	MHz
F _{MAX_BRAM_RF_DELAYED_WRITE}	Block RAM (Read first, Delayed_write mode) When in SDP RF mode and there is possibility of overlap between port A and port B addresses	528.26	477.33	400.80	317.36	MHz
F _{MAX_CAS_WF_NC}	Block RAM Cascade (Write first, No change mode) When cascade but not in RF mode	551.27	493.83	408.00	322.48	MHz
F _{MAX_CAS_RF_PERFORMANCE}	Block RAM Cascade (Read first, Performance mode) When in cascade with RF mode and no possibility of address overlap/one port is disabled	551.27	493.83	408.00	322.48	MHz
F _{MAX_CAS_RF_DELAYED_WRITE}	When in cascade RF mode and there is a possibility of address overlap between port A and port B	478.27	427.35	350.88	267.38	MHz
F _{MAX_FIFO}	FIFO in all modes without ECC	601.32	543.77	458.09	372.44	MHz
F _{MAX_ECC}	Block RAM and FIFO in ECC configuration	484.26	430.85	351.12	254.13	MHz

Notes:

1. TRACE will report all of these parameters as T_{RCKO_DO}.
2. T_{RCKO_DOR} includes T_{RCKO_DOW}, T_{RCKO_DOPR}, and T_{RCKO_DOPW} as well as the B port equivalent timing parameters.
3. These parameters also apply to synchronous FIFO with DO_REG = 0.
4. T_{RCKO_DO} includes T_{RCKO_DOP} as well as the B port equivalent timing parameters.
5. These parameters also apply to multirate (asynchronous) and synchronous FIFO with DO_REG = 1.
6. T_{RCKO_FLAGS} includes the following parameters: T_{RCKO_AEMPTY}, T_{RCKO_AFULL}, T_{RCKO_EMPTY}, T_{RCKO_FULL}, T_{RCKO_RDERR}, T_{RCKO_WRERR}.
7. T_{RCKO_POINTERS} includes both T_{RCKO_RDCOUNT} and T_{RCKO_WRCOUNT}.
8. The ADDR setup and hold must be met when EN is asserted (even when WE is deasserted). Otherwise, block RAM data corruption is possible.
9. These parameters include both A and B inputs as well as the parity inputs of A and B.
10. T_{RCO_FLAGS} includes the following flags: AEMPTY, AFULL, EMPTY, FULL, RDERR, WRERR, RDCOUNT, and WRCOUNT.
11. RDEN and WREN must be held Low prior to and during reset. The FIFO reset must be asserted for at least five positive clock edges of the slowest clock (WRCLK or RDCLK).

Clock Buffers and Networks

Table 33: Global Clock Switching Characteristics (Including BUFGCTRL)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T_BCCCK_CE/T_BCCKC_CE ⁽¹⁾	CE pins Setup/Hold	0.12/0.30	0.14/0.38	0.26/0.38	0.23/0.40	ns
T_BCCCK_S/T_BCCKC_S ⁽¹⁾	S pins Setup/Hold	0.12/0.30	0.14/0.38	0.26/0.38	0.23/0.40	ns
T_BGCKO_O ⁽²⁾	BUFGCTRL delay from I0/I1 to O	0.08	0.10	0.12	0.10	ns
Maximum Frequency						
F _{MAX_BUFG}	Global clock tree (BUFG)	741.00	710.00	625.00	560.00	MHz

Notes:

1. T_{BCCCK_CE} and T_{BCCKC_CE} must be satisfied to assure glitch-free operation of the global clock when switching between clocks. These parameters do not apply to the BUFGMUX primitive that assures glitch-free operation. The other global clock setup and hold times are optional; only needing to be satisfied if device operation requires simulation matches on a cycle-for-cycle basis when switching between clocks.
2. T_{BGCKO_O} (BUFG delay from I0 to O) values are the same as T_{BCCKO_O} values.

Table 34: Input/Output Clock Switching Characteristics (BUFIO)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T_BLOCKO_O	Clock to out delay from I to O	1.04	1.14	1.32	1.48	ns
Maximum Frequency						
F _{MAX_BUFIO}	I/O clock tree (BUFIO)	800.00	800.00	710.00	710.00	MHz

Table 35: Regional Clock Buffer Switching Characteristics (BUFR)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T_BRCKO_O	Clock to out delay from I to O	0.60	0.65	0.77	1.06	ns
T_BRCKO_O_BYP	Clock to out delay from I to O with Divide Bypass attribute set	0.30	0.32	0.38	0.57	ns
T_BRDO_O	Propagation delay from CLR to O	0.71	0.75	0.96	0.93	ns
Maximum Frequency						
F _{MAX_BUFR} ⁽¹⁾	Regional clock tree (BUFR)	600.00	540.00	450.00	450.00	MHz

Notes:

1. The maximum input frequency to the BUFR is the BUFIO F_{MAX} frequency.

Table 36: Horizontal Clock Buffer Switching Characteristics (BUFH)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T _{BHCKO_O}	BUFH delay from I to O	0.10	0.11	0.13	0.12	ns
T _{BHCKC_CE} /T _{BHCKC_CE}	CE pin Setup and Hold	0.20/0.16	0.23/0.20	0.38/0.21	0.28/0.09	ns
Maximum Frequency						
F _{MAX_BUHF}	Horizontal clock buffer (BUFH)	741.00	710.00	625.00	560.00	MHz

Table 37: Duty Cycle Distortion and Clock-Tree Skew

Symbol	Description	Device	Speed Grade				Units
			1.0V		0.9V		
			-3	-2/-2L	-1	-2L	
T _{DCD_CLK}	Global Clock Tree Duty Cycle Distortion ⁽¹⁾	All	0.20	0.20	0.20	0.25	ns
T _{CKSKEW}	Global Clock Tree Skew ⁽²⁾	XC7K70T	0.29	0.40	0.40	0.47	ns
		XC7K160T	0.42	0.53	0.57	0.59	ns
		XC7K325T	0.59	0.74	0.79	0.91	ns
		XC7K355T	0.45	0.57	0.59	0.69	ns
		XC7K410T	0.60	0.74	0.79	0.91	ns
		XC7K420T	0.60	0.74	0.79	0.91	ns
		XC7K480T	0.60	0.74	0.79	0.91	ns
T _{DCD_BUFIO}	I/O clock tree duty cycle distortion	All	0.12	0.12	0.12	0.12	ns
T _{BUFIOSKEW}	I/O clock tree skew across one clock region	All	0.02	0.02	0.02	0.03	ns
T _{DCD_BUFR}	Regional clock tree duty cycle distortion	All	0.15	0.15	0.15	0.15	ns

Notes:

1. These parameters represent the worst-case duty cycle distortion observable at the I/O flip flops. For all I/O standards, IBIS can be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times.
2. The T_{CKSKEW} value represents the worst-case clock-tree skew observable between sequential I/O elements. Significantly less clock-tree skew exists for I/O registers that are close to each other and fed by the same or adjacent clock-tree branches. Use the Xilinx Timing Analyzer tools to evaluate clock skew specific to your application.

Table 38: MMCM Specification (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T _{MMCMDCK_DEN} / T _{MMCMCKD_DEN}	DEN Setup/Hold	1.76/0.00	1.97/0.00	2.29/0.00	2.40/0.00	ns, Min
T _{MMCMDCK_DWE} / T _{MMCMCKD_DWE}	DWE Setup/Hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T _{MMCMCKO_DRDY}	CLK to out of DRDY	0.65	0.72	0.99	0.70	ns, Max
F _{DCK}	DCLK frequency	200.00	200.00	200.00	100.00	MHz, Max

Notes:

1. The MMCM does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
2. The static offset is measured between any MMCM outputs with identical phase.
3. Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
4. Includes global clock buffer.
5. Calculated as F_{VCO}/128 assuming output duty cycle is 50%.
6. When CLKOUT4_CASCADE = TRUE, MMCM_F_{OUTMIN} is 0.036 MHz.

PLL Switching Characteristics

Table 39: PLL Specification

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
PLL_F _{INMAX}	Maximum Input Clock Frequency	1066.00	933.00	800.00	800.00	MHz
PLL_F _{INMIN}	Minimum Input Clock Frequency	19.00	19.00	19.00	19.00	MHz
PLL_F _{INJITTER}	Maximum Input Clock Period Jitter	< 20% of clock input period or 1 ns Max				
PLL_F _{INDUTY}	Allowable Input Duty Cycle: 19—49 MHz	25.00	25.00	25.00	25.00	%
	Allowable Input Duty Cycle: 50—199 MHz	30.00	30.00	30.00	30.00	%
	Allowable Input Duty Cycle: 200—399 MHz	35.00	35.00	35.00	35.00	%
	Allowable Input Duty Cycle: 400—499 MHz	40.00	40.00	40.00	40.00	%
	Allowable Input Duty Cycle: >500 MHz	45.00	45.00	45.00	45.00	%
PLL_F _{VCOMIN}	Minimum PLL VCO Frequency	800.00	800.00	800.00	800.00	MHz
PLL_F _{VCOMAX}	Maximum PLL VCO Frequency	2133.00	1866.00	1600.00	1600.00	MHz
PLL_F _{BANDWIDTH}	Low PLL Bandwidth at Typical ⁽¹⁾	1.00	1.00	1.00	1.00	MHz
	High PLL Bandwidth at Typical ⁽¹⁾	4.00	4.00	4.00	4.00	MHz
PLL_T _{STATPHAOFFSET}	Static Phase Offset of the PLL Outputs ⁽²⁾	0.12	0.12	0.12	0.12	ns
PLL_T _{OUTJITTER}	PLL Output Jitter	Note 3				
PLL_T _{OUTDUTY}	PLL Output Clock Duty Cycle Precision ⁽⁴⁾	0.20	0.20	0.20	0.25	ns
PLL_T _{LOCKMAX}	PLL Maximum Lock Time	100	100	100	100	μs
PLL_F _{OUTMAX}	PLL Maximum Output Frequency	1066.00	933.00	800.00	800.00	MHz
PLL_F _{OUTMIN}	PLL Minimum Output Frequency ⁽⁵⁾	6.25	6.25	6.25	6.25	MHz
PLL_T _{EXTFDVAR}	External Clock Feedback Variation	< 20% of clock input period or 1 ns Max				
PLL_RST _{MINPULSE}	Minimum Reset Pulse Width	5.00	5.00	5.00	5.00	ns

Table 39: PLL Specification (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
PLL_F_PFDMAX	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized	550.00	500.00	450.00	450.00	MHz
	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	300.00	300.00	300.00	300.00	MHz
PLL_F_PFDMIN	Minimum Frequency at the Phase Frequency Detector	19.00	19.00	19.00	19.00	MHz
PLL_T_FBDelay	Maximum Delay in the Feedback Path	3 ns Max or one CLKIN cycle				
Dynamic Reconfiguration Port (DRP) for PLL Before and After DCLK						
T_PLLCCK_DADDR/ T_PLLCKC_DADDR	Setup and hold of D address	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_PLLCCK_DI/ T_PLLCKC_DI	Setup and hold of D input	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_PLLCCK_DEN/ T_PLLCKC_DEN	Setup and hold of D enable	1.76/0.00	1.97/0.00	2.29/0.00	2.40/0.00	ns, Min
T_PLLCCK_DWE/ T_PLLCKC_DWE	Setup and hold of D write enable	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_PLLCKO_DRDY	CLK to out of DRDY	0.65	0.72	0.99	0.70	ns, Max
F_DCK	DCLK frequency	200.00	200.00	200.00	100.00	MHz, Max

Notes:

1. The PLL does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
2. The static offset is measured between any PLL outputs with identical phase.
3. Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
4. Includes global clock buffer.
5. Calculated as $F_{VCO}/128$ assuming output duty cycle is 50%.

Additional Package Parameter Guidelines

The parameters in this section provide the necessary values for calculating timing budgets for Kintex-7 FPGA clock transmitter and receiver data-valid windows.

Table 50: Package Skew

Symbol	Description	Device	Package	Value	Units
$T_{PKGSKEW}$	Package Skew ⁽¹⁾	XC7K70T	FBG484	108	ps
			FBG676	135	ps
		XC7K160T	FBG484	118	ps
			FBG676	136	ps
			FFG676	161	ps
		XC7K325T	FBG676	146	ps
			FFG676	154	ps
			FBG900	163	ps
			FFG900	161	ps
		XC7K355T	FFG901	149	ps
		XC7K410T	FBG676	165	ps
			FFG676	168	ps
			FBG900	151	ps
			FFG900	146	ps
		XC7K420T	FFG901	149	ps
			FFG1156	145	ps
		XC7K480T	FFG901	149	ps
			FFG1156	145	ps

Notes:

1. These values represent the worst-case skew between any two SelectIO resources in the package: shortest delay to longest delay from die pad to ball.
2. Package delay information is available for these device/package combinations. This information can be used to deskew the package.

Table 53: GTX Transceiver Performance (Cont'd)

Symbol	Description	Output Divider	Speed Grade								Units	
			1.0V				0.9V					
			-3	-2/-2L	-1 ⁽¹⁾	-2L ⁽²⁾						
			Package Type									
FF	FB	FF	FB	FF	FB	FF	FB	FF	FB	FF	GHz	
F _{GQPLL RANGE2}	GTX transceiver QPLL frequency range 2		9.8–12.5	9.8–10.3125	N/A	N/A						

Notes:

1. The -1 speed grade requires a 4-byte internal data width for operation above 5.0 Gb/s.
2. The -2L (0.9V) speed grade requires a 4-byte internal data width for operation above 3.8 Gb/s.
3. Data rates between 8.0 Gb/s and 9.8 Gb/s are not available.
4. For QPLL line rate range 2, the maximum line rate with the divider N set to 66 is 10.3125Gb/s.

Table 54: GTX Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade				Units	
		1.0V		0.9V			
		-3	-2/-2L	-1	-2L		
F _{GTXDRPCLK}	GTXDRPCLK maximum frequency	175.01	175.01	156.25	125.00	MHz	

Table 55: GTX Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F _{GCLK}	Reference clock frequency range	-3 speed grade	60	—	700	MHz
		All other speed grades	60	—	670	MHz
T _{RCLK}	Reference clock rise time	20% – 80%	—	200	—	ps
T _{FCLK}	Reference clock fall time	80% – 20%	—	200	—	ps
T _{DCREF}	Reference clock duty cycle	Transceiver PLL only	40	50	60	%

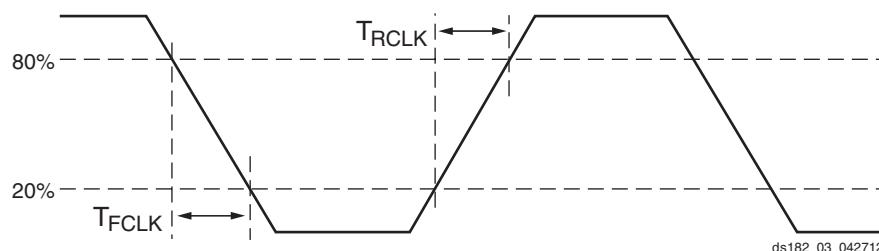


Figure 3: Reference Clock Timing Parameters

Table 58: GTX Transceiver Transmitter Switching Characteristics (Cont'd)

Symbol	Description	Condition	Min	Typ	Max	Units
TJ _{10.3125}	Total Jitter ⁽²⁾⁽⁴⁾	10.3125 Gb/s	—	—	0.28	UI
DJ _{10.3125}	Deterministic Jitter ⁽²⁾⁽⁴⁾		—	—	0.17	UI
TJ _{9.953}	Total Jitter ⁽²⁾⁽⁴⁾	9.953 Gb/s	—	—	0.28	UI
DJ _{9.953}	Deterministic Jitter ⁽²⁾⁽⁴⁾		—	—	0.17	UI
TJ _{9.8}	Total Jitter ⁽²⁾⁽⁴⁾	9.8 Gb/s	—	—	0.28	UI
DJ _{9.8}	Deterministic Jitter ⁽²⁾⁽⁴⁾		—	—	0.17	UI
TJ _{8.0}	Total Jitter ⁽²⁾⁽⁴⁾	8.0 Gb/s	—	—	0.30	UI
DJ _{8.0}	Deterministic Jitter ⁽²⁾⁽⁴⁾		—	—	0.15	UI
TJ _{6.6_QPLL}	Total Jitter ⁽²⁾⁽⁴⁾	6.6 Gb/s	—	—	0.28	UI
DJ _{6.6_QPLL}	Deterministic Jitter ⁽²⁾⁽⁴⁾		—	—	0.17	UI
TJ _{6.6_CPLL}	Total Jitter ⁽³⁾⁽⁴⁾	6.6 Gb/s	—	—	0.30	UI
DJ _{6.6_CPLL}	Deterministic Jitter ⁽³⁾⁽⁴⁾		—	—	0.15	UI
TJ _{5.0}	Total Jitter ⁽³⁾⁽⁴⁾	5.0 Gb/s	—	—	0.30	UI
DJ _{5.0}	Deterministic Jitter ⁽³⁾⁽⁴⁾		—	—	0.15	UI
TJ _{4.25}	Total Jitter ⁽³⁾⁽⁴⁾	4.25 Gb/s	—	—	0.30	UI
DJ _{4.25}	Deterministic Jitter ⁽³⁾⁽⁴⁾		—	—	0.15	UI
TJ _{3.75}	Total Jitter ⁽³⁾⁽⁴⁾	3.75 Gb/s	—	—	0.30	UI
DJ _{3.75}	Deterministic Jitter ⁽³⁾⁽⁴⁾		—	—	0.15	UI
TJ _{3.2}	Total Jitter ⁽³⁾⁽⁴⁾	3.20 Gb/s ⁽⁵⁾	—	—	0.2	UI
DJ _{3.2}	Deterministic Jitter ⁽³⁾⁽⁴⁾		—	—	0.1	UI
TJ _{3.2L}	Total Jitter ⁽³⁾⁽⁴⁾	3.20 Gb/s ⁽⁶⁾	—	—	0.32	UI
DJ _{3.2L}	Deterministic Jitter ⁽³⁾⁽⁴⁾		—	—	0.16	UI
TJ _{2.5}	Total Jitter ⁽³⁾⁽⁴⁾	2.5 Gb/s ⁽⁷⁾	—	—	0.20	UI
DJ _{2.5}	Deterministic Jitter ⁽³⁾⁽⁴⁾		—	—	0.08	UI
TJ _{1.25}	Total Jitter ⁽³⁾⁽⁴⁾	1.25 Gb/s ⁽⁸⁾	—	—	0.15	UI
DJ _{1.25}	Deterministic Jitter ⁽³⁾⁽⁴⁾		—	—	0.06	UI
TJ ₅₀₀	Total Jitter ⁽³⁾⁽⁴⁾	500 Mb/s	—	—	0.1	UI
DJ ₅₀₀	Deterministic Jitter ⁽³⁾⁽⁴⁾		—	—	0.03	UI

Notes:

1. Using same REFCLK input with TX phase alignment enabled for up to 12 consecutive transmitters (three fully populated GTX Quads).
2. Using QPLL_FBDIV = 40, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
3. Using CPLL_FBDIV = 2, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
4. All jitter values are based on a bit-error ratio of $1e^{-12}$.
5. CPLL frequency at 3.2 GHz and TXOUT_DIV = 2.
6. CPLL frequency at 1.6 GHz and TXOUT_DIV = 1.
7. CPLL frequency at 2.5 GHz and TXOUT_DIV = 2.
8. CPLL frequency at 2.5 GHz and TXOUT_DIV = 4.

Table 63: CEI-6G and CEI-11G Protocol Characteristics

Description	Line Rate (Mb/s)	Interface	Min	Max	Units
CEI-6G Transmitter Jitter Generation					
Total transmitter jitter ⁽¹⁾	4976–6375	CEI-6G-SR	–	0.3	UI
		CEI-6G-LR	–	0.3	UI
CEI-6G Receiver High Frequency Jitter Tolerance					
Total receiver jitter tolerance ⁽¹⁾	4976–6375	CEI-6G-SR	0.6	–	UI
		CEI-6G-LR	0.95	–	UI
CEI-11G Transmitter Jitter Generation					
Total transmitter jitter ⁽²⁾	9950–11100	CEI-11G-SR	–	0.3	UI
		CEI-11G-LR/MR	–	0.3	UI
CEI-11G Receiver High Frequency Jitter Tolerance					
Total receiver jitter tolerance ⁽²⁾	9950–11100	CEI-11G-SR	0.65	–	UI
		CEI-11G-MR	0.65	–	UI
		CEI-11G-LR	0.825	–	UI

Notes:

1. Tested at most commonly used line rate of 6250 Mb/s using 390.625 MHz reference clock.
2. Tested at line rate of 9950 Mb/s using 155.46875 MHz reference clock and 11100 Mb/s using 173.4375 MHz reference clock.

Table 64: SFP+ Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
SFP+ Transmitter Jitter Generation				
Total transmitter jitter	9830.40 ⁽¹⁾	–	0.28	UI
	9953.00			
	10312.50			
	10518.75			
	11100.00			
SFP+ Receiver Frequency Jitter Tolerance				
Total receiver jitter tolerance	9830.40 ⁽¹⁾	0.7	–	UI
	9953.00			
	10312.50			
	10518.75			
	11100.00			

Notes:

1. Line rated used for CPRI over SFP+ applications.

Table 67: XADC Specifications (Cont'd)

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
XADC Reference⁽⁵⁾						
External Reference	V _{REFP}	Externally supplied reference voltage	1.20	1.25	1.30	V
On-Chip Reference		Ground V _{REFP} pin to AGND, T _j = -40°C to 100°C	1.2375	1.25	1.2625	V

Notes:

- Offset and gain errors are removed by enabling the XADC automatic gain calibration feature. The values are specified for when this feature is enabled.
- Only specified for new BitGen option XADCEnhancedLinearity = ON.
- See the ADC chapter in [UG480: 7 Series FPGAs XADC User Guide](#) for a detailed description.
- See the Timing chapter in [UG480: 7 Series FPGAs XADC User Guide](#) for a detailed description.
- Any variation in the reference voltage from the nominal V_{REFP} = 1.25V and V_{REFN} = 0V will result in a deviation from the ideal transfer function. This also impacts the accuracy of the internal sensor measurements (i.e., temperature and power supply). However, for external ratiometric type applications allowing reference to vary by ±4% is permitted. On-chip reference variation is ±1%.

Configuration Switching Characteristics

Table 68: Configuration Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Power-up Timing Characteristics						
T _{PL} ⁽¹⁾	Program latency	5	5	5	5	ms, Max
T _{POR} ⁽¹⁾	Power-on reset (50 ms ramp rate time)	10/50	10/50	10/50	10/50	ms, Min/Max
	Power-on reset (1 ms ramp rate time)	10/35	10/35	10/35	10/35	ms, Min/Max
T _{PROGRAM}	Program pulse width	250	250	250	250	ns, Min
CCLK Output (Master Mode)						
T _{ICCK}	Master CCLK output delay	150	150	150	150	ns, Min
T _{MCCKL}	Master CCLK clock Low time duty cycle	40/60	40/60	40/60	40/60	%, Min/Max
T _{MCCKH}	Master CCLK clock High time duty cycle	40/60	40/60	40/60	40/60	%, Min/Max
F _{MCCCK}	Master CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
	Master CCLK frequency for AES encrypted x16	50.00	50.00	50.00	35.00	MHz, Max
F _{MCCK_START}	Master CCLK frequency at start of configuration	3.00	3.00	3.00	3.00	MHz, Typ
F _{MCCKTOL}	Frequency tolerance, master mode with respect to nominal CCLK	±50	±50	±50	±50	%, Max
CCLK Input (Slave Modes)						
T _{SCCKL}	Slave CCLK clock minimum Low time	2.50	2.50	2.50	2.50	ns, Min
T _{SCCKH}	Slave CCLK clock minimum High time	2.50	2.50	2.50	2.50	ns, Min
F _{SCCK}	Slave CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
EMCCLK Input (Master Mode)						
T _{EMCCKL}	External master CCLK Low time	2.50	2.50	2.50	2.50	ns, Min
T _{EMCCKH}	External master CCLK High time	2.50	2.50	2.50	2.50	ns, Min
F _{EMCCK}	External master CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
Internal Configuration Access Port						
F _{ICAPCK}	Internal configuration access port (ICAPE2)	100.00	100.00	100.00	70.00	MHz, Max

Revision History

The following table shows the revision history for this document:

Date	Version	Description
03/01/11	1.0	Initial Xilinx release.
04/01/11	1.1	Added the XC7K355T, XC7K420T, and XC7K480T devices throughout data sheet. Added the extended temperature range discussion to page 1 . Updated V_{CCAUX_IO} in Table 2 . Edits to clarify Power-On/Off Power Supply Sequencing power sequencing discussion. Added I_{CCAUX_IO} and I_{CCBRAM} to Table 6 and Table 7 . Updated MMCM_ F_{INDUTY} and added $F_{INJITTER}$, $T_{OUTJITTER}$, $T_{EXTFDVAR}$, and Note 3 to Table 38 . Removed the SBG324 package from Table 50 . Updated the Notice of Disclaimer .
10/04/11	1.2	Replaced -1L with -2L throughout this data sheet. Updated Min/Max values and removed Note 5 from Table 2 . Clarified Power-On/Off Power Supply Sequencing power sequencing discussion including adding $T_{VCO2VCCAUX}$ to Table 8 . Updated V_{ICM} in Table 12 and Table 13 . Added Note 1 to table 12. Updated Table 69 including adding Note 1 . Added <i>Absolute Maximum Ratings for GTX Transceivers</i> . Revised the reference clock maximum frequency (F_{GCLK}) in Table 55 . Added Table 57 . Added LVTTL and removed SSTL135_II and SSTL15_II specifications from Table 19 . Removed HSTL_III from Table 20 . Removed the <i>I/O Standard Adjustment Measurement Methodology</i> section. Use IBIS for more accurate information and measurements. Updated $T_{IDELAYPAT_JIT}$ in Table 26 . Added T_{AS}/T_{AH} to Table 28 . Added $T_{RDCK_DI_WF_NC}/T_{RCKD_DI_WF_NC}$ and $T_{RDCK_DI_RF}/T_{RCKD_DI_RF}$ to Table 31 . Completely updated Table 68 . Updated the AC Switching Characteristics in Table 19 , Table 20 , Table 21 , Table 22 , Table 23 , Table 24 , Table 26 through Table 38 , Table 40 though Table 37 , and Table 67 .
11/03/11	1.3	Revised the V_{OCM} specification in Table 12 . Updated the AC Switching Characteristics based upon the ISE 13.3 v1.02 speed specification throughout document including Table 19 and Table 20 . Added MMCM_ $T_{FBDELAY}$ while adding MMCM_ to the symbol names of a few specifications in Table 38 and PLL to the symbol names in Table 39 . In Table 40 through Table 47 , updated the pin-to-pin descriptions with the SSTL15 standard. Updated units in Table 49 .
02/13/12	1.4	Updated summary description on page 1 . In Table 2 , revised V_{CCO} for the 3.3V HR I/O banks and updated T_j . Added typical values to Table 3 . Updated the notes in Table 6 . Added MGTAVCC, MGTAVTT, and MGTVCCAUX power supply ramp times to Table 8 . Rearranged Table 9 , added Mobile_DDR, HSTL_I_18, HSTL_II_18, HSUL_12, SSTL135_R, SSTL15_R, and SSTL12 and removed DIFF_SSTL135, DIFF_SSTL18_I, DIFF_SSTL18_II, DIFF_HSTL_I, and DIFF_HSTL_II. Added Table 10 and Table 11 . Revised the specifications in Table 12 and Table 13 . Updated the eFUSE Programming Conditions section and removed the endurance table. Added the IO_FIFO Switching Characteristics table. Revised I_{CCADC} and updated Note 1 in Table 67 . Revised DDR LVDS transmitter data width in Table 16 . Updated the AC Switching Characteristics based upon the ISE 13.4 v1.03 speed specification throughout document. Removed notes from Table 28 as they are no longer applicable. Updated specifications in Table 68 . Updated Note 1 in Table 37 . In the GTX Transceiver DC Input and Output Levels section: Revised V_{IN} , and added I_{DCIN} and I_{DCOUT} to Table 51 . Added Note 4 to Table 53 . In Table 55 , revised F_{GCLK} , removed T_{PHASE} , and added T_{DLOCK} . Revised specifications and added Note 2 to Table 57 . Added Table 58 and Table 59 along with GTX Transceiver Protocol Jitter Characteristics in Table 60 through Table 65 .
05/23/12	1.5	Reorganized entire data sheet including adding Table 44 and Table 48 . Updated T_{SOL} in Table 1 . Updated I_{BATT} and added R_{IN_TERM} to Table 3 . Added values to Table 6 and Table 7 . Updated Power-On/Off Power Supply Sequencing , page 6 with regards to GTX transceivers. Updated many parameters in Table 9 including SSTL135 and SSTL135_R. Removed V_{OX} column and added DIFF_HSUL_12 to Table 11 . Updated V_{OL} in Table 12 . Updated Table 16 and removed notes 2 and 3. Updated Table 17 . Updated the AC Switching Characteristics based upon the ISE 14.1 v1.04 for the -3, -2, -2L (1.0V), -1, and -2L (0.9V) speed specifications throughout the document. In Table 31 , updated Reset Delays section including Note 10 and Note 11 . Added data for T_{LOCK} and T_{DLOCK} in Table 55 . Updated many of the XADC specifications in Table 67 and added Note 2 . Updated and moved <i>Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK</i> section from Table 68 to Table 38 and Table 39 .